

FQA90N15 / FQA90N15_F109 N-Channel QFET MOSFET 150 V, 90 A, 18 mΩ

Description

This N-Channel enhancement mode power MOSFET is produced using Fairchild Semiconductor[®]'s proprietary planar stripe and DMOS technology. This advanced MOSFET technology has been especially tailored to reduce on-state resistance, and to provide superior switching performance and high avalanche energy strength. These devices are suitable for switched mode power supplies, audio amplifier, DC motor control, and variable switching power applications.

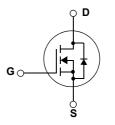
Features

• 90 A, 150 V, $R_{DS(on)}$ = 18 m Ω (Max)@V_{GS} = 10 V, I_D = 45 A

March 2013

- Low Gate Charge (typical 220 nC)
- · Low Crss (typical 200 pF)
- 100% Avalanche Tested
- 175°C Maximum Junction Temperature Rating





Absolute Maximum Ratings

Symbol	Parameter	FQA90N15_F109	Unit V	
V _{DSS}	Drain-Source Voltage	150		
I _D	Drain Current - Continuous ($T_C = 25^{\circ}C$)	90	А	
	- Continuous (T _C = 100°C)		63.5	А
I _{DM}	Drain Current - Pulsed	(Note 1)	360	А
V _{GSS}	Gate-Source Voltage	± 25	V	
E _{AS}	Single Pulsed Avalanche Energy	(Note 2)	1400	mJ
I _{AR}	Avalanche Current	(Note 1)	90	А
E _{AR}	Repetitive Avalanche Energy	(Note 1)	37.5	mJ
dv/dt	Peak Diode Recovery dv/dt (Note 3)		6.0	V/ns
P _D	Power Dissipation (T _C = 25°C)	375	W	
	- Derate above 25°C	2.5	W/°C	
T _J , T _{STG}	Operating and Storage Temperature Range	-55 to +175	°C	
Τ _L	Maximum lead temperature for soldering purposes 1/8" from case for 5 seconds	300	°C	

Thermal Characteristics

Symbol	Parameter	Тур	Max	Unit	
R _{0JC} Thermal Resistance, Junction-to-Case			0.4	°C/W	
$R_{\theta CS}$	S Thermal Resistance, Case-to-Sink			°C/W	
R _{0JA} Thermal Resistance, Junction-to-Ambient			40	°C/W	

Device Marking FQA90N15		Device	Packag	e Reel Size Tap		e Width		Quantity		
		FQA90N15_F109	TO-3PN	I					30	
Electric	al Cha	racteristics T _c	= 25°C unless othe	erwise noted						
Symbol		Parameter		Test Conditions		Min	Тур	Max	Unit	
Off Charac	teristics							1	1	
BV _{DSS}	Drain-Source Breakdown Voltage		V_{GS} = 0 V, I _D = 250 µA		150			V		
ΔBV _{DSS} / ΔT _J	Breakdown Voltage Temperature Coefficient		I _D = 250	$I_D = 250 \ \mu$ A, Referenced to 25°C			0.15		V/°C	
5		ate Voltage Drain Current		V _{DS} = 150 V, V _{GS} = 0 V				1	μA	
			V _{DS} = 120 V, T _C = 125°C					10	μA	
I _{GSSF}	Gate-Boo	ly Leakage Current, Fo	orward	V _{GS} = 2	5 V, V _{DS} = 0 V				100	nA
I _{GSSR}	Gate-Boo	te-Body Leakage Current, Reverse		V_{GS} = -25 V, V_{DS} = 0 V				-100	nA	
On Charact	eristics									
V _{GS(th)}	Gate Thre	Threshold Voltage		V_{DS} = V_{GS} , I_D = 250 μ A		2.0		4.0	V	
R _{DS(on)}	Static Dra	Prain-Source On-Resistance		V _{GS} = 10 V, I _D = 45 A			0.014	0.018	Ω	
9 _{FS}	Forward	Transconductance		$V_{DS} = 40 \text{ V}, I_D = 45 \text{ A}$ (Note 4)			68		S	
Dynamic Ch	naracteristi	ics		-				1	1	
C _{iss}	Input Cap	Input Capacitance		$V_{DS} = 25 V, V_{GS} = 0 V,$			6700	8700	pF	
C _{oss}	Output C	apacitance		f = 1.0 MHz				1400	1800	pF
C _{rss}	Reverse	Transfer Capacitance						200	260	pF
Switching C	haracteris	tics		-				1		
t _{d(on)}	Turn-On	n-On Delay Time		$V_{DD} = 75 \text{ V}, I_D = 90\text{ A},$			105	220	ns	
t _r	Turn-On	Rise Time		- R _G = 25 Ω - (Note 4, 5)			760	1500	ns	
t _{d(off)}	Turn-Off	Delay Time					470	950	ns	
t _f	Turn-Off	Fall Time					410	830	ns	
Q _g	Total Gat	e Charge		V _{DS} = 120 V, I _D = 90A,				220	285	nC
Q _{gs}	Gate-Sou	Irce Charge		V _{GS} = 1	V _{GS} = 10 V			43		nC
Q _{gd}		in Charge		(Note 4, 5)			110		nC	
		haracteristics and Max	vimum Ratings	<u>.</u>				110		
I _S		n Continuous Drain-So	•		rent				90	Α
I _{SM}	Maximum Pulsed Drain-Source Diode Forward							360	A	
V _{SD}		urce Diode Forward Vo		1	V. Is = 90 A				1.5	V
t _{rr}		Recovery Time		$V_{GS} = 0 V, I_S = 90 A$ $V_{GS} = 0 V, I_S = 90 A,$			175		ns	
Q _{rr}		Recovery Charge			$V_{GS} = 0 V, I_S = 90 A,$ $dI_F / dt = 100 A/\mu s$ (Note			0.97		μΟ

NOTES:

1. Repetitive Rating : Pulse width limited by maximum junction temperature

2. L = 0.29mH, I_{AS} =90A, V_{DD} = 25V, R_G = 25 $\Omega,$ Starting T_J = 25°C

3. I_{SD} \leq 90A, di/dt \leq 300A/µs, V_{DD} \leq BV_{DSS,} Starting ~T_J = 25°C

4. Pulse Test : Pulse width $\leq 300 \mu s,$ Duty cycle $\leq 2\%$

5. Essentially independent of operating temperature

Notes : 1. V_{DS} = 30V 2. 250µ s Pulse Test

Notes : 1. V_{GS} = 0V 2. 250µ s Pulse Tes

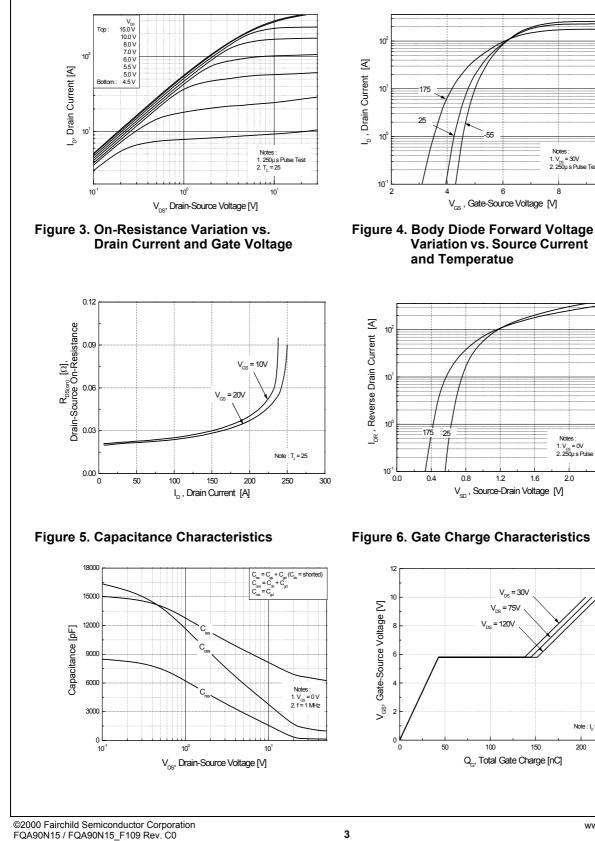
2.4

2.0

1.6

10

8



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250

Note : $I_{D} = 90 \text{ A}$

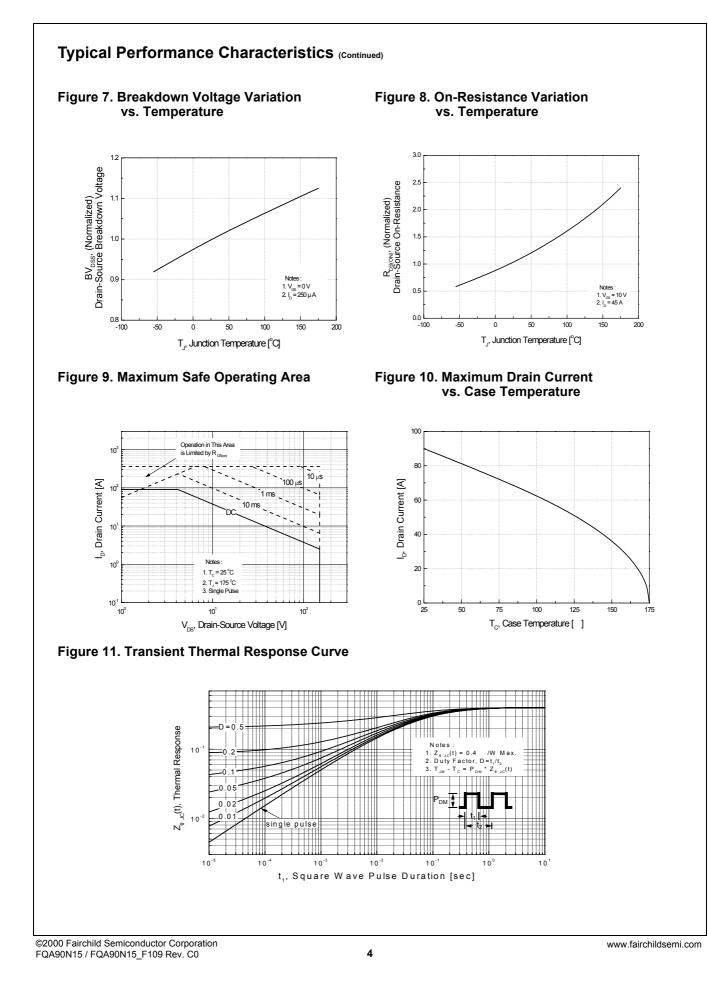
200

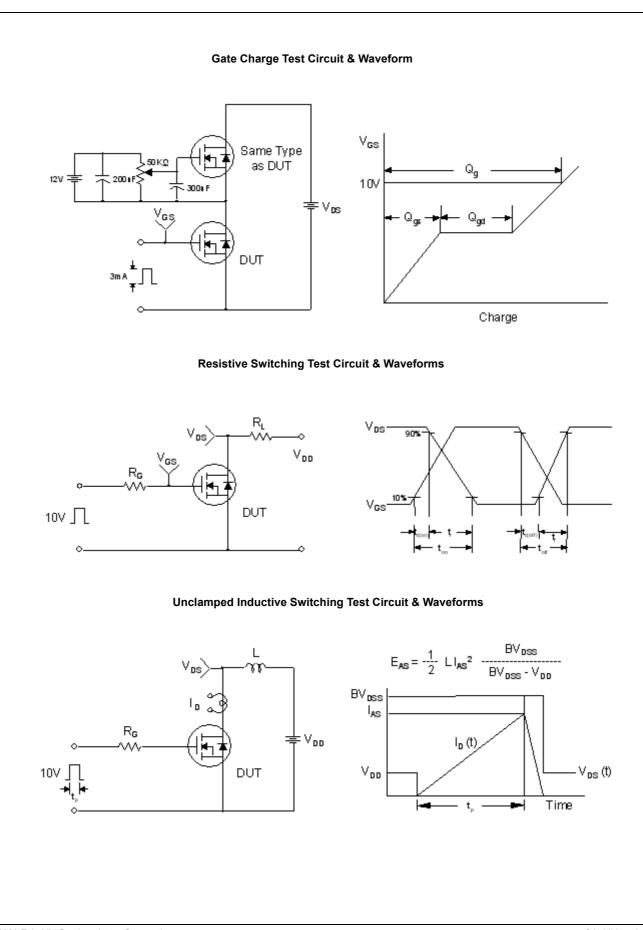
150

Figure 2. Transfer Characteristics

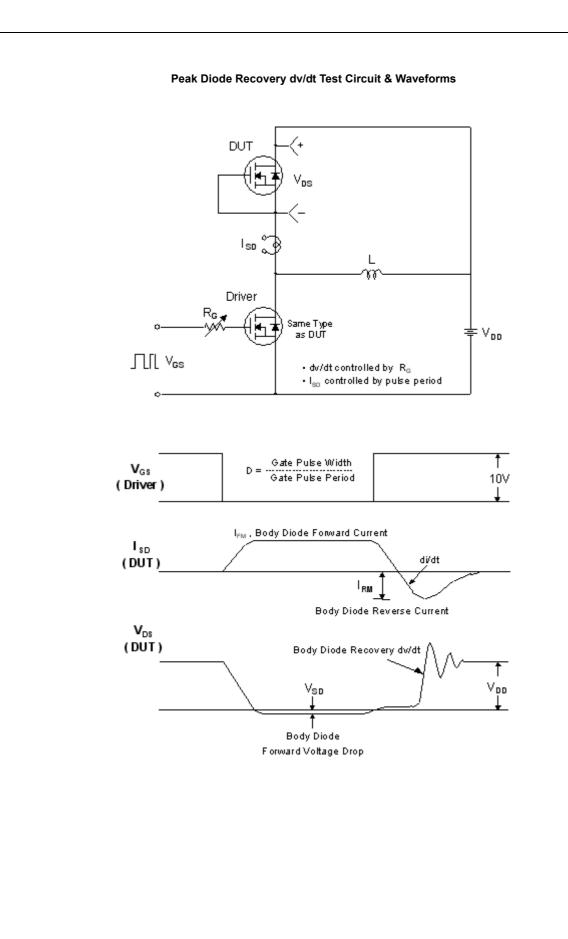
Typical Performance Characteristics

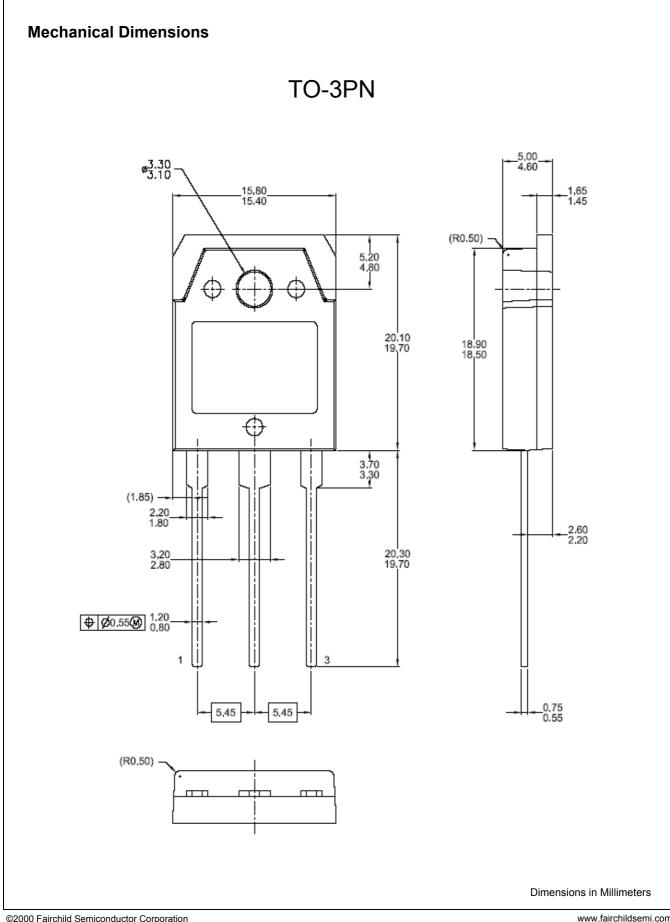
Figure 1. On-Region Characteristics





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